

Marvin Test Solutions to Feature Expanded Semiconductor Test Capabilities at ITC 2016

TS-960e Test Platform Offers Advanced RF, Digital, Mixed-Signal Test Capabilities and Software Tools

Irvine, Calif. – November 9, 2016 – [Marvin Test Solutions](#), a trusted provider of globally deployed, innovative test solutions for military, aerospace, and manufacturing organizations, will feature its [TS-960e](#) Semiconductor Test Platform, the newest addition to the TS-960 Series, at the International Test Conference 2016 (ITC), November 15 – 17, in Fort Worth, TX.

The TS-960e is a flexible, open-architecture semiconductor test solution which offers PXI Express performance and digital, mixed-signal and RF test capabilities in a compact, single-chassis footprint. ATEasy® test development and test executive software provides an easy-to-use integrated software environment to reduce development time.

The TS-960e is now available with Keysight Technologies' comprehensive range of PXIe RF instrumentation to address a range of RF applications including WLAN, Bluetooth, Cellular, EW, and RF transceivers. Available instrumentation options include vector transceivers, vector signal analyzers and generators, and vector network analyzers offering wafer and packaged RF test capabilities from 9 KHz to 27 GHz. All of these modules as well Keysight's VSA measurement application software are fully integrated with ATEasy to provide a complete solution.

"Our semiconductor test solutions offer an alternative to expensive, big-iron ATE systems, delivering the features of high-end ATE with the open architecture and benefits of the PXI standard," said Steve Sargeant, CEO of Marvin Test Solutions. "The TS-960e offers the flexibility to include both PXI and PXIe modules and, with the addition of Keysight's portfolio of PXIe RF instruments, enables our customers to configure a compact solution with the advanced capabilities they need."

Proven Test Platform

The TS-960e platform features a 21-slot, 3U PXI Express chassis accommodating up to 256 125 MHz digital I/O channels with PMUs per pin, yet has a small footprint and modular structure, allowing users to address a range of test applications. Available as a bench top or with an integrated manipulator, the TS-960e takes full advantage of the PXIe architecture to achieve a full-featured test solution for digital, mixed – signal or RF test applications.

High-Performance Digital Test and Comprehensive Software Tools

The base TS-960e platform uses the advanced [GX5296](#) - a 3U PXI, 32 channel 125 MHz digital I/O card featuring timing and PMU per pin capability with sub-nanosecond edge placement resolution. The GX5296 delivers high-performance digital test capabilities and is ideal for addressing verification, focused production, and failure analysis test needs - or for replacing legacy test systems. The GX5296 builds on the successful [GX5295](#) PXI digital subsystem, offering unrivaled timing, density, memory, and sub-nanosecond timing per pin capabilities. And with the addition of MTS' advanced software tools for program development / debug and comprehensive file conversion tools for WGL, VCD/eVCD, STIL, and ATP formats, the TS-960e provides no-compromise digital / mixed-signal test capabilities for component, SoC and SiP devices.

ITC 2016

ITC, known as the cornerstone of Test Week™, is dedicated to the electronic test of devices, boards and systems, covering the complete cycle from design verification, test, diagnosis, failure analysis and back to



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process and design improvement. This year's event will take place November 15 - 17 at the Fort Worth Convention Center. Marvin Test Solutions is exhibiting in Booth 311, and will participate in the Corporate Forum with a presentation entitled "Leveraging the PXI Modular Architecture for ATE Platforms". To register for the event, visit www.itctestweek.org.

Contact:

Marvin Test Solutions, Inc.

info@MarvinTest.com

<http://www.MarvinTest.com/>

Linda Holtkamp

(949) 263-2222

LindaH@MarvinTest.com

1-888-837-8297

About Marvin Test Solutions

Marvin Test Solutions is a vertically integrated aerospace test and measurement company that has delivered innovative solutions for factory, flightline, intermediate-level, and depot-level applications since 1988. As a member of the Marvin Group, an award-winning aerospace company with a 50-year history in the Defense and Commercial Aerospace industries, Marvin Test Solutions has test systems deployed in the defense, commercial aircraft, transportation, space, and semiconductor manufacturing markets. As an aerospace test and measurement company with a solution-centric focus, our portfolio of PXI hardware, test software, and complete automated test systems offers the performance, flexibility, innovation, value, and long-term support demanded by our customers. Our ATE test solutions offer a broad range of capabilities for component, board-level, and system-level products, including test solutions for digital and mixed-signal test.